## **PCT**

#### WORLD INTELLECTUAL PROPERTY ORGANIZATION International Bureau



# INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(51) International Patent Classification 6: G05B 13/02

A1

(11) International Publication Number:

WO 97/36215

(43) International Publication Date:

2 October 1997 (02.10.97)

(21) International Application Number:

PCT/US97/03859

(22) International Filing Date:

13 March 1997 (13.03.97)

(30) Priority Data:

08/623,569

28 March 1996 (28.03.96)

US

(71) Applicant: ROSEMOUNT INC. [US/US]; 12001 Technology Drive, Eden Prairie, MN 55344 (US).

(72) Inventors: ERYUREK, Evren; 4952 York Avenue South, Minneapolis, MN 55410 (US). WARRIOR, Jogesh; 7423 Frontier Trail, Chanhassen, MN 55317 (US).

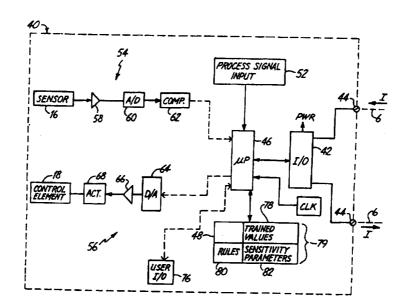
(74) Agents: CHAMPLIN, Judson, K. et al.; Westman, Champlin & Kelly, P.A., International Centre - Suite 1600, 900 Second Avenue South, Minneapolis, MN 55402-3319 (US).

(81) Designated States: BR, CN, JP, SG, European patent (AT, BE, CH, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL,

#### **Published**

With international search report.

(54) Title: DEVICE IN A PROCESS SYSTEM FOR DETECTING EVENTS



#### (57) Abstract

A process device (40) couples to a process control loop (6). The process device (40) receives process signals. A memory (48) in the process device (40) contains a nominal parameter value (78) and a rule (80). Computing circuitry (46) calculates a statistical parameter of the process signal and operates on the statistical parameter and the stored nominal value (78) based upon the stored rule (80) and responsively provides an event output based upon the operation. Output circuitry (42) provides an output in response to the event output.

## FOR THE PURPOSES OF INFORMATION ONLY

Codes used to identify States party to the PCT on the front pages of pamphlets publishing international applications under the PCT.

AL	Albania	ES	Spain	LS	Lesotho	SI	Slovenia
AM	Armenia	FI	Finland	LT	Lithuania	SK	Slovakia
AT	Austria	FR	France	LU	Luxembourg	SN	Senegal
AU	Australia	GA	Gabon	LV	Latvia	SZ'	Swaziland
AZ	Azerbaijan	GB	United Kingdom	MC	Monaco	TD	Chad
BA	Bosnia and Herzegovina	GE	Georgia	MD	Republic of Moldova	TG	Togo
BB	Barbados	GH	Ghana	MG	Madagascar	TJ	Tajikistan
BE	Belgium	GN	Guinea	MK	The former Yugoslav	TM	Turkmenistan
BF	Burkina Faso	GR	Greece		Republic of Macedonia	TR	Turkey
BG		HU	Hungary	ML	Mali	TT	Trinidad and Tobago
BJ	Bulgaria Benin	IE	Ireland	MN	Mongolia	UA	Ukraine
BR	Brazil	IL	Israel	MR	Mauritania	UG	Uganda
		IS	Iceland	MW	Malawi	US	United States of America
BY	Belarus	IT	Italy	MX	Mexico	UZ	Uzbekistan
CA	Canada	JP	•	NE	Niger	VN	Viet Nam
CF	Central African Republic	KE	Japan Vanus	NL	Netherlands	YU	Yugoslavia
CG	Congo	KG	Kenya	NO	Norway	zw	Zimbabwe
CH	Switzerland	KP	Kyrgyzstan	NZ	New Zealand		
CI	Côte d'Ivoire	Kr	Democratic People's	PL	Poland		
CM	Cameroon	7/10	Republic of Korea	PT	Portugal		
CN	China	KR	Republic of Korea	RO	Romania		
CU	Cuba	KZ	Kazakstan	RU	Russian Federation		
CZ	Czech Republic	LC	Saint Lucia		Sudan		
DE	Germany	LI	Liechtenstein	SD			
DK	Denmark	LK	Sri Lanka	SE	Sweden		
EE	Estonia	LR	Liberia	SG	Singapore		

-1-

# DEVICE IN A PROCESS SYSTEM FOR DETECTING EVENTS

## BACKGROUND OF THE INVENTION

The present invention relates to devices which couple to process control loops of the type used in industry. More specifically, the invention relates to detection of events in a process control system by monitoring process signals.

Process control loops are used in industry to control operation of a process, such as an oil refinery. 10 A transmitter is typically part of the loop and is located in the field to measure and transmit a process variable such as pressure, flow or temperature, for example, to control room equipment. A controller such as a valve controller is also part of the process 15 control loop and controls position of a valve based upon a control signal received over the control loop or generated internally. Other controllers control electric motors or solenoids for example. The control room equipment is also part of the process control loop 20 such that an operator or computer in the control room is capable of monitoring the process based upon process variables received from transmitters in the field and responsively controlling the process by sending control signals to the appropriate control devices. 25 process device which may be part of a control loop is a portable communicator which is capable of monitoring and transmitting process signals on the process control Typically, these are used to configure devices 30 which form the loop.

It is desirable to detect the occurrence of an event in the process control system. Typically, the prior art has been limited to a simple detection

PCT/US97/03859 WO 97/36215

-2-

For example, process variable such as techniques. pressure is monitored and an alarm is sounded or a safety shutdown is initiated if the process variable exceeds predefined limits. However, in order to identify what event triggered the alarm, it is necessary to use complex models which are difficult to implement in a process environment where there is limited power and resources for large computations.

5

10

15

20

25

## SUMMARY OF THE INVENTION

A device in a process control system includes an input which receives a process signal. The device includes memory containing nominal parameter values and In one embodiment, a nominal parameter value relates to trained value(s) of the process signal and sensitivity parameter(s). Computing circuitry in the device calculates statistical parameters of the process signal and operates on the statistical parameters and the stored nominal parameter values based upon the stored rules. The computing circuitry provides an event output related to an event in the process control system based upon the evaluation of the rules. circuitry provides an output in response to the event In one embodiment, the statistical parameters are selected from the group consisting of standard deviation, mean, sample variance, range, root-meansquare, and rate of change. In one embodiment the rules are selected to detect events from the group consisting of signal spike, signal drift, signal bias, signal noise, signal stuck, signal hard over, cyclic signal, erratic signal and non-linear signal. 30

The device of the present invention includes any process device such as a transmitter, controller, motor, sensor, valve, communicator, or control room equipment.

- -3-

### BRIEF DESCRIPTION OF THE DRAWINGS

Figure 1 is a simplified diagram showing a process control loop including a transmitter, controller, hand-held communicator and control room.

Figure 2 is a block diagram of a process device in accordance with the present invention.

5

10

15

Figure 3 is a diagram showing application of rules to calculated statistical parameters and sensitivity parameters to provide a process event output.

Figure 4 is a graph of a process signal output versus time showing various types of events.

Figure 5 is a block diagram showing an inference engine operating on process events in accordance with the present invention.

Figure 6 is a simplified block diagram of an inference engine for use in the present invention.

## DETAILED DESCRIPTION OF THE PREFERRED EMBODIMENTS

Process variables are typically the primary 20 variables which are being controlled in a process. used herein, process variable means any variable which describes the condition of the process such as, for example, pressure, flow, temperature, product level, pH, turbidity, vibration, position, motor current, any other characteristic of the process, etc. 25 Control signal means any signal (other than a process variable) which is used to control the process. For example, control signal means a desired process variable value (i.e. a setpoint) such as a desired temperature, pressure, flow, product level, pH or turbidity, etc., which is adjusted 30 by a controller or used to control the process. Additionally, a control signal means, calibration values, alarms, alarm conditions, the signal which is provided to a control element such as a valve position

. -4-

5

10

15

20

25

30

signal which is provided to a valve actuator, an energy level which is provided to a heating element, a solenoid on/off signal, etc., or any other signal which relates to control of the process. A diagnostic signal as used herein includes information related to operation of devices and elements in the process control loop, but does not include process variables or control signals. For example, diagnostic signals include valve stem position, applied torque or force, actuator pressure, pressure of a pressurized gas used to actuate a valve, resistance, current, power, voltage, electrical capacitance, inductance, device temperature, stiction, friction, full on and off positions, travel, frequency, amplitude, spectrum and spectral components, stiffness, field strength, duration, magnetic electric or electric motor back emf, intensity, motion, current, loop related parameters (such as control loop resistance, voltage, or current), or any other parameter which may be detected or measured in the system. Furthermore, process signal means any signal which is related to the process or element in the process such as, for example, a process variable, a control signal or a diagnostic signal. Process devices include any device which forms part of or couples to a process control loop and is used in the control or monitoring of a process.

Figure 1 is a diagram showing an example of a process control system 2 which includes process piping 4 which carries a process fluid and two wire process control loop 6 carrying loop current I. A transmitter 8, controller 10, which couples to a final control element in the loop such as an actuator, valve, a pump, motor or solenoid, communicator 12, and control room 14 are all part of process control loop 6. It is understood that loop 6 is shown in one configuration and

any appropriate process control loop may be used such as a 4-20 mA loop, 2, 3 or 4 wire loop, multi-drop loop and a loop operating in accordance with the HART®, Fieldbus or other digital or analog communication protocol. operation, transmitter 8 senses a process variable such as flow using sensor 16 and transmits the sensed process variable over loop 6. The process variable may be received by controller/valve actuator 10, communicator 12 and/or control room equipment 14. Controller 10 is shown coupled to valve 18 and is capable of controlling 10 the process by adjusting valve 18 thereby changing the flow in pipe 4. Controller 10 receives a control input over loop 6 from, for example, control room 14, transmitter 8 or communicator 12 and responsively 15 adjusts valve 18. In another embodiment, controller 10 internally generates the control signal based upon process signals received over loop 6. Communicator 12 may be the portable communicator shown in Figure 1 or may be a permanently mounted process unit which monitors the process and performs computations. Process devices 20 include, for example, transmitter 8 (such as a 3095 transmitter available from Rosemount Inc.), controller 10, communicator 12 and control room 14 shown in Figure 1. Another type of process device is a PC, programmable logic unit (PLC) or other computer coupled to the loop using appropriate I/O circuitry to allow monitoring, managing, and/or transmitting on the loop.

Any of the process devices 8, 10, 12 or 14 shown in Figure 1 may include event monitoring circuitry in accordance with the present invention. Figure 2 is a block diagram of a process device 40 forming part of loop 6. Device 40 is shown generically and may comprise any process device such as transmitter 8, controller 10, communicator 12 or control room equipment 14. Control

25

30

-6-

5

10

15

20

25

30

room equipment 14 may comprise, for example, a DCS system implemented with a PLC and controller 10 may also comprise a "smart" motor and pump. Process device 40 includes I/O circuitry 42 coupled to loop 6 at terminals I/O circuitry has preselected input and output impedance known in the art to facilitate appropriate communication from and to device 40. Device 40 includes microprocessor 46, coupled to I/O circuitry 42, memory 48 coupled to microprocessor 46 and clock 50 coupled to microprocessor 46. Microprocessor 46 receives a process signal input 52. Block input is intended to signify input of any process signal, and as explained above, the process signal input may be a process variable, or a control signal and may be received from loop 6 using I/O circuitry 42 or may be generated internally within field device 40. Field device 40 is shown with a sensor input channel 54 and a control channel 56. Typically, a transmitter such as transmitter 8 will exclusively include sensor input channel 54 while a controller such as controller 10 will exclusively include a control Other devices on loop 6 such 56. channel communicator 12 and control room equipment 14 may not include channels 54 and 56. It is understood that device 40 may contain a plurality of channels to monitor a plurality of process variables and/or control a plurality of control elements as appropriate.

Sensor input channel 54 includes sensor 16, sensing a process variable and providing a sensor output to amplifier 58 which has an output which is digitized by analog to digital converter 60. Channel 54 is typically used in transmitters such as transmitter 8. Compensation circuitry 62 compensates the digitized signal and provides a digitized process variable signal to microprocessor 46. In one embodiment, channel 54

-7-

comprises a diagnostic channel which receives a diagnostic signal.

5

10

15

20

25

30

When process device 40 operates controller such as controller 8, device 40 includes control channel 56 having control element 18 such as a valve, for example. Control element 18 is coupled to microprocessor 46 through digital to analog converter 64, amplifier 66 and actuator 68. Digital to analog converter 64 digitizes a command output microprocessor 46 which is amplified by amplifier 66. Actuator 68 controls the control element 18 based upon the output from amplifier 66. In one embodiment, actuator 68 is coupled directly to loop 6 and controls a source of pressurized gas (not shown) to position control element 18 in response to the current I flowing through loop 6. In one embodiment, controller 10 includes control channel 56 to control a control element and also includes sensor input channel 54 which provides a diagnostic signal such as valve stem position, force, torque, actuator pressure, pressure of a source of pressurized air, etc.

In one embodiment, I/O circuitry 42 provides a power output used to completely power other circuitry in process device 40 using power received from loop 6. Typically, field devices such as transmitter 8, or controller 10 are powered off the loop 6 while communicator 12 or control room 14 has a separate power source. As described above, process signal input 52 provides a process signal to microprocessor 46. The process signal may be a process variable from sensor 16, the control output provided to control element 18, a diagnostic signal sensed by sensor 16, or a control signal, process variable or diagnostic signal received

. -8-

over loop 6, or a process signal received or generated by some other means such as another I/O channel.

5

10

15

A user I/O circuit 76 is also connected to microprocessor 46 and provides communication between device 40 and a user. Typically, user I/O circuit 76 includes a display and audio for output and a keypad for Typically, communicator 12 and control room 14 includes I/O circuit 76 which allows a user to monitor and input process signals such as process variables, control signals (setpoints, calibration values, alarms, alarm conditions, etc.) along with rules, sensitivity parameters and trained values as described below. user may also use circuit 76 in communicator 12 or control room 14 to send and receive such process signals to transmitter 8 and controller 10 over loop 6. Further, such circuitry could be directly implemented in transmitter 8, controller 10 or any other process device 40.

Microprocessor 46 acts in accordance with instructions stored in memory 48. Memory 48 also 20 contains trained values 78, rules 80 and sensitivity parameters 82 in accordance with the present invention. The combination of the sensitivity parameters 82 and the trained values 78 provide a nominal value 79. Figure 3 is a block diagram 83 showing a logical implementation 25 of device 40. Logical block 84 receives process signals and calculates statistical parameters for the process signals. These statistical parameters include standard mean, sample variance, root-mean-square deviation, (RMS), range ( $\Delta R$ ) and rate of change (ROC) of the 30 process signal, for example. These are given by the following equations:

-9-

$$mean = \overline{x} = \frac{1}{N} \sum_{i=1}^{N} X_i$$
 Eq. 1

$$RMS - \sqrt{\frac{1}{N} \sum_{i=1}^{N} X_i^2}$$
 Eq. 2

 $\sqrt{\sigma} = \sqrt{\text{standard deviation}} = variance$ 

$$=S^2 - \frac{1}{n-1} \sum_{i=1}^{N} (x_i - \overline{x})^2$$

Eq. 3

$$ROC=r_i = \frac{X_i - X_{i-1}}{T}$$
 Eq. 4

5

10

15

20

$$\Delta R = X_{MAX} - X_{MIN}$$
 Eq. 5

Where N is the total number of data points in the sample period,  $x_i$  and  $x_{i-1}$  are two consecutive values of the process signal and T is the time interval between the two values. Further,  $x_{MAX}$  and  $x_{MIN}$  are the respective maximum and minimum of the process signal over a sampling or training time period. These statistical parameters are calculated alone or in any combination. It will be understood that the invention includes any statistical parameter other than those explicitly set forth which may be implemented to analyze a process signal. The calculated statistical parameter is received by rule calculation block 86 which operates in accordance with rules 80 stored in memory 48. Rules block 86 also receives trained values 78 from memory 48.

. -10-

5

10

15

20

25

30

Trained values are the nominal or (i.e., typical) statistical parameter value for the process signal and comprise the same statistical parameters (standard deviation, mean, sample variance, root-mean-square (RMS), range and rate of change, etc.) used in logical block 84. In one embodiment, the trained values are provided by the manufacturer and stored in memory 48 of transmitter 40 during manufacture. embodiment, the trained values are periodically updated by addressing device 40 over loop 6. In still another embodiment, input circuitry 76 may generate or receive the trained values or be used to transmit the trained values to another process device over loop 6. another embodiment, the trained values are generated by statistical parameter logical block 84 which generates, or learns, the nominal or normal statistical parameters normal operation of the process. statistical parameters are used to generate the trained values 78 in memory 48 for future use. This allows dynamic adjustment of trained values 78 for each specific loop and operating condition. In this embodiment, statistical parameters 84 are monitored for a user selectable period of time based upon the process dynamic response time.

Rules block 86 receives sensitivity parameters 82 from memory 48. Rules logical block 86 provides examples of a number of different rules. Each sensitivity parameter value 82 provides an acceptable range or relationship as determined by the appropriate rule between the calculated statistical parameters 84 and the appropriate trained values 78. The sensitivity parameter values 82 may be set by the manufacturer, received over loop 6 or input using input circuitry 76. The sensitivity parameters are adjusted for the specific

. -11-

application. For example, in process control applications where high accuracy is required, sensitivity parameters are set so as to allow only small variations of the process signals relative to the trained values. The use of sensitivity parameters allow the diagnostic and event detection decision making to be controlled based upon the particular process and the requirements of the user.

Figure 4 is an example of a process signal versus time which shows different process events (e.g. 10 normal, bias, drift, noise, spike and stuck) which are detected using the present invention. The process signal shown in Figure 4 is initially in a normal state and then moves to a bias condition. Next, the process signal goes through a drift condition followed by a noisy signal condition. Finally, a series of spike events occur in the process signal followed by a stuck condition. The rules used to detect these events are described below.

20

25

30

15

5

### Drift

Drift occurs when a process signal changes over time from its true (i.e. nominal) value. embodiment of the invention includes a rule which operates on a statistical parameter mean  $(\mu)$ , trained parameter mean  $(\mu')$  and a tuning parameter alpha  $(\alpha)$  to detect drift.

Drift sensitivity is controlled by a single sensitivity parameter, alpha  $(\alpha)$ . Alpha  $(\alpha)$  represents a percentage above or below the normal mean signal level that is tolerable before a drift or event is detected. The following rule performed by rule calculation block 86 detects a drift event:

. -12-

if  $\mu < \mu'$  (1- $\alpha$ ) then a negative drift event if  $\mu > \mu'$  (1+ $\alpha$ ) then a positive drift event,

where  $\mu$  is the current mean of the process signal from 84,  $\mu'$  is the trained mean from 78 and  $\alpha$  is the sensitivity parameter from 82 which defines the acceptable variations from the mean. Additionally, the mean is monitored over time. A drift event is only detected if, over a series of consecutive sampling period, the mean is moving away from the trained value. The trained mean  $(\mu')$  may be learned by training device 40 during normal operation of the process.

#### **Bias**

5

10

Bias is the result of a temporary drift "stabilizing" at a certain level above or below the expected signal level. Once the drift stops, the resulting signal has a bias, sometimes called an offset from the true/nominal value. A bias is detected using the same rule used for drift. Additionally, the mean is monitored over time. If the mean is not continuing to move away from the trained mean  $(\mu')$ , then it is determined that the event is bias, not drift.

#### 25 Noise

30

A different combination of a rule, tuning parameters and trained values detect noise in the process signal. Noise detection sensitivity is adjusted by adjusting the sensitivity parameter beta  $(\beta)$ . Beta  $(\beta)$  is the amount the current standard deviation  $(\sigma)$  can be above the trained standard deviation  $(\sigma')$  before detection of a noise event. For example, if the user desires to detect a noise event when the process signal is twice as noisy as the trained value,  $\beta$  should be sent

- 13-

to 2.0. Range  $(\Delta R)$  is also used by the rule to differentiate noise from normal signal variations. An example rule for noise detection is:

if  $\sigma > \beta \sigma'$  and if  $\Delta R > \Delta R'$  then noise detected.

Where  $\sigma$  and  $\sigma'$  are the current and trained standard deviation  $\Delta R$  and  $\Delta R'$  are the current and trained range, respectively, and  $\beta$  is the noise sensitivity parameter.

#### Stuck

10

15

20

25

Yet another combination of a rule, statistical value, tuning parameters and trained values detect a stuck condition in a process signal. A "stuck" process signal is one which a condition of the process signal does not vary with time. Stuck sensitivity controlled by adjusting the sensitivity parameter 82 gamma  $(\gamma)$ . A value for gamma  $(\gamma)$  is expressed as a percentage of the trained standard deviation  $(\sigma')$  and represents how small a change in standard deviation from the trained value triggers detection of a stuck event. For example, if a user wishes to detect a stuck condition when the process signal noise level is half of the trained value,  $\gamma$  should be set equal to 50 percent (0.5). Further, range of the signal ( $\Delta R$ ) can be used to eliminate errors that arise with small signals. example rule is:

If  $(\sigma + \Delta R) \le \gamma(\sigma' + \Delta R')$  then a stuck event is detected.

- . -14-

#### Spike

different combination of a rule, statistical value, trained value and sensitivity parameter is used to detect a spike event. A spike event occurs when the signal momentarily goes to an Sensitivity to spikes in the process extreme value. signal is controlled by adjusting a sensitivity parameter from  $\delta$  stored in 82.  $\delta$  is the acceptable trained maximum rate of change  $(\Delta P_{\text{max}})$  between two consecutive data points. For example, if the user wishes to detect any spikes that have a rate of change (ROC) from block 84 that is 30% greater than  $\Delta r_{\text{max}}$  from block 78 relative to the trained value,  $\delta$  from 82 should be set to 1.30. An example rule is:

15

10

5

if ROC >  $\delta \cdot \Delta r_{MAX}$  then a spike event is detected

Other rules include a cyclic rule to detect cyclical oscillations in the process signal and an 20 erratic rule to detect erratic behavior in the process signal. It should be understood that other rules may be implemented to observe other events in the process signal and may use different formulas or computational techniques to detect and event. A rule may operate on 25 more than one statistical parameter or on more than one process signal. For example, if a process variable such as flow rate exceeds a predetermined limit while another process variable such as process temperature spikes, a rule could determine that the process is overheating and 30 down condition could shut emergency Furthermore, another type of rule is implemented in fuzzy logic in which the statistical parameter is

. -15-

operated on by a sensitivity parameter which is a membership function applied to the trained values.

5

10

15

20

25

30

All of the rules discussed herein provide a process event output based upon the operation of the rule. It should be understood that the process event output may have a plurality of discrete or continuous values based upon operation of the rule. Note that the combination of the sensitivity parameter and the trained value provides a nominal parameter value and that the rule operates on the nominal parameter value and the The various process signals, statistical parameter. parameters and trained values can be combined using or appropriate fuzzy logic. averages weighted Membership functions include, for example, trapezoidal and triangular functions. For example, the statistical parameter can be mapped onto the chosen membership These are then used during training to function. generate the trained values, and to generate the statistical parameters for use by the rules.

In one embodiment, the trained values are obtained by determining that the process is stable, and generating the statistical parameters for a selectable period of time. These are stored as the trained values. The selectable period of time should be about the same as sampling period or block used to generate the statistical parameters during operation. This process may be user initiated or automated.

The output of a rule can be transmitted over loop 6, output on user I/O circuit 76, stored for future use, used as an input to another computation such as another rule or a control function, or used in any appropriate manner. In another embodiment, the present invention monitors related process signals and performs comparisons and correlations between these signals. For

- . -16-

example, in Figure 2 process signals such as the output of A/D converter 60, compensation circuit 62, and current I through loop 6 can be analyzed in accordance with Figure 3. For example, the plurality of process signals should all be within a desired tolerance between one another as set forth by the appropriate combination of sensitivity parameters, rules, and trained values.

10

15

20

25

30

Figure 5 is a block diagram 100 showing inference engine 102. Inference engine 102 resides in process device 40, is part of loop 6, and receives process variables 104, control signals 106 and process events 108. Process events are detected in accordance with the present invention. Inference engine 102 includes computation circuitry 110 and process data 112. Process data 112 may comprise, for example, process history information such as logged process variables, control signals, process events or other process signals and may contain process specific information which further defines the process being monitored. Upon the occurrence of a process event, the inference engine 102 determines which component in the various process devices is faulty. Computation circuitry 110 analyzes process variables 104, control signals 106, process events 108 and other process signals to determine the cause of the process event. Computation circuitry operates in accordance with a series of rules such as those used in the known technique of an expert system. Computation circuitry 110 operates on all of the inputs including process data 112 and provides a faulty element output such as a warning signal. For example, if a drift event is detected, inference engine 102 operates to determine the cause of the drifts. For example, the drift may be due to a control setpoint which was changed in which case computation circuitry 110 determines that 5

10

15

20

25

30

the control loop is operating properly. However, if the setpoint was not changed, the inference engine further analyzes the various inputs and, for example, checks the integrity of the device reporting a process event, such as a valve motor, pump, vibration equipment, etc., by running appropriate diagnostics. If the valve, for example, indicates that the valve is operating properly, inference engine may then perform transmitter diagnostics to determine if a transmitter and associated sensors are operating properly. These diagnostics may observe information from the specific element being reviewed and may also observe information being received from other sources on the control loop such as upstream or downstream sensors, etc. Computation circuitry 110 uses any appropriate computational technique such a series of rules, fuzzy logic or neural networks. preferred embodiment, inference engine is implemented in a microprocessor and memory and may be located in a control room, at some remote location or in the field itself. Inference engine 102 may be implemented in any of the process devices 8, 10, 12 or 14 shown in Figure The faulty element output can be provided to an operator or can be used by additional computational circuitry which performs further diagnostics on the loop.

Figure 6 shows a block diagram 200 of a simplified, example inference engine such as engine 102 operating in accordance with a rule base. Upon the occurrence of a process event, at block 202 the inference engine 102 examines the process event to identify the specific event which was detected. If the event was a drift event, control moves on to block 204. If the event was some other event such as spike, noise or bias, control moves to a rule base constructed in

PCT/US97/03859 WO 97/36215

-18-

5

10

15

20

accordance with the specific event which was detected. At block 204, the inference engine checks to see if the setpoint of the process was recently changed. If the setpoint was recently changed, an output is provided which indicates that the process is operating within its normal range and that the drift which was detected was due to the change in setpoint. However, if the setpoint was not changed, the inference engine moves on to block 206 to run further diagnostics. At block 206, the inference engine instructs process device 40 to run on board diagnostics to further determine the cause of the At block 208, if the diagnostics run by device 40 identify the cause of the drift, the inference engine provides an output identifying a faulty component. However, if the diagnostics indicate that device 40 is operating properly, inference engine instructs related devices to run diagnostics at block 210. For example, downstream, be upstream or devices may related 212, At block controllers or transmitters. inference engine determines if one of the related process devices is the faulty device. If the fault which caused the drift is one of the related devices, the inference engine provides an output identifying the device and faulty component. If none of the related devices are in error, the inference engine observes 25 other process signals at block 214 in an attempt to identify known process conditions at block 216. cause of the drift is due to a known process condition, for example, a fluid pressure drop caused by the filling of a reserve tank with process fluid. If the process 30 specific condition known, the condition is If the process condition is not known, the identified. operator is informed that a drift event has been detected whose cause cannot be identified. At any point

-19-

in the flow chart 200, based upon any of the various rules, the inference engine may initiate a shutdown procedure to shut down the process. As discussed above, actual inference engines will contain a much more sophisticated rule base and/or will employ more sophisticated forms of logic such as fuzzy logic and neural networks, specific to each process control application.

5

Although the present invention has described with reference to preferred embodiments, 10 workers skilled in the art will recognize that changes may be made in form and detail without departing from the spirit and scope of the invention. For example, all of the various functions and circuitry described herein implemented in any appropriate circuitry 15 including software, ASICs, fuzzy logic techniques, or even analog implementations. Further, the process device may include any number or combination of input and control channels and may operate on any number of process signals, alone or in their combination, and the 20 rules may operate accordingly.

- . -20-

## WHAT IS CLAIMED IS:

1. A process device coupled to a process control loop, comprising:

a process signal input means for providing a process signal related to a process;

memory containing a nominal parameter value
 and a rule;

parameter of the digitized process variable and operating on the statistical parameter and the nominal parameter value based upon the rule and providing an event output in response to an event in the process detected based upon the operation; and

output circuitry outputting the event output.

- 2. The apparatus of claim 1 wherein the nominal parameter value comprises a trained value and a sensitivity parameter.
- 3. The apparatus of claim 1 wherein the process control loop is selected from the group consisting of two wire process control loops, three wire process control loops and four wire process control loops.
- 4. The apparatus of claim 1 wherein the device is completely powered with power received from the process control loop.
- 5. The apparatus of claim 1 wherein the statistical parameter is selected from the group consisting of standard deviation, mean, sample variance, root-mean-square (RMS), range, and rate of change.
- 6. The apparatus of claim 1 wherein the computing circuitry provides the event output based upon a plurality of statistical parameters.

- · -21-

- 7. The apparatus of claim 1 wherein the rule is selected from the group consisting of spike, drift, bias, noise and stuck.
- 8. The apparatus of claim 1 wherein the computing circuitry comprises fuzzy logic and the rule employs a membership function.
- 9. The apparatus of claim 8 including a fuzzy membership function stored in the memory and wherein computation circuitry applies the membership function to the statistical parameter prior to operation of the rule.
- 10. The apparatus of claim 1 wherein the process signal input means comprises a sensor input channel and the process signal comprises a process variable.
- 11. The apparatus of claim 10 wherein the sensor input channel includes:
  - a sensor providing a sensor output related to the process; and
  - an analog to digital converter which converts the sensor output into a digitized process variable.
- 12. The apparatus of claim 11 wherein the sensor is selected from the group consisting of pressure, temperature, pH, flow, turbidity, level sensors, position, conductivity, motor current, motor back emf and vibration.
- 13. The apparatus of claim 1 wherein the process signal input means comprises a control channel and the process signal comprises a control signal.
- 14. The apparatus of claim 13 wherein the control channel includes:
  - a control element for controlling the process; and

- -22-

an actuator for actuating the control element.

- 15. The apparatus of claim 1 wherein the process signal input means comprises input circuitry coupled to the control loop to receive the process signal from the process control loop.
- 16. The apparatus of claim 1 wherein the output circuitry couples to the process control loop and transmits the event output on the process control loop.
- 17. The apparatus of claim 1 wherein the output circuitry comprises user output circuitry for outputting the event output to a user.
- 18. The apparatus of claim 1 wherein process signal input means comprises a diagnostic channel and the process signal comprises a diagnostic signal related to a control element used to control the process.
- 19. The apparatus of claim 18 wherein the diagnostic signal is selected from the group consisting of valve stem position, force, and pressure.
- The apparatus of claim 14 wherein the actuator comprises a motor and the control element comprises a pump operated by the motor.
- 21. The apparatus of claim 1 including an inference engine coupled to the event output for performing diagnostics on the process control loop.
- 22. The apparatus of claim 2 wherein the computing circuitry monitors the statistical parameter during normal operation of the process control loop and thereby generates the trained value.
- 23. A transmitter in a process control loop, comprising:
  - a sensor sensing a process variable;

- an analog to digital converter coupled to the sensor having a digitized process variable output;
- a memory containing a nominal parameter value
   and a rule;
- computation circuitry coupled to the memory and the analog to digital converter, the computation circuitry calculating a statistical parameter of the digitized processed variable, operating on the statistical parameter based upon the rule and the nominal parameter and responsively providing a process event output; and
- output circuitry coupled to the process control loop outputting the process event output onto the loop.
- 24. The transmitter of claim 23 wherein the nominal parameter value comprises a trained value and a sensitivity parameter.
- 25. The transmitter of claim 23 wherein the device is completely powered with power received from the process control loop.
- 26. The transmitter of claim 23 wherein the rule is selected from the group consisting of signal spike, signal drift, signal bias, signal noise and signal stuck.
- 27. The transmitter of claim 23 wherein the sensor is selected from the group consisting of pressure, pH, flow, turbidity and level sensors.
- 28. The transmitter of claim 23 including compensation circuitry coupled to the analog to digital converter for compensating the digitized process variable.

- 29. The transmitter of claim 24 wherein the computing circuitry monitors the statistical parameter during normal operation of the process control loop and thereby generates the trained value.
- 30. A method performed in a process device for detecting a process event in a process control system, comprising:

obtaining a process signal related to a process;

retrieving a rule from a memory;

retrieving a nominal parameter from the memory;

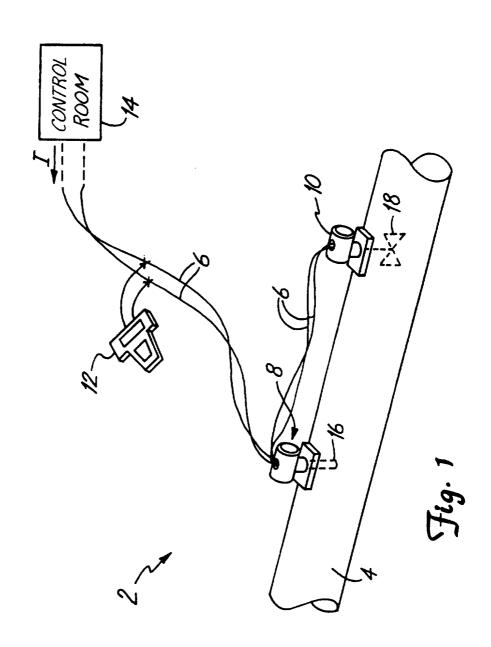
calculating a statistical parameter of the process signal;

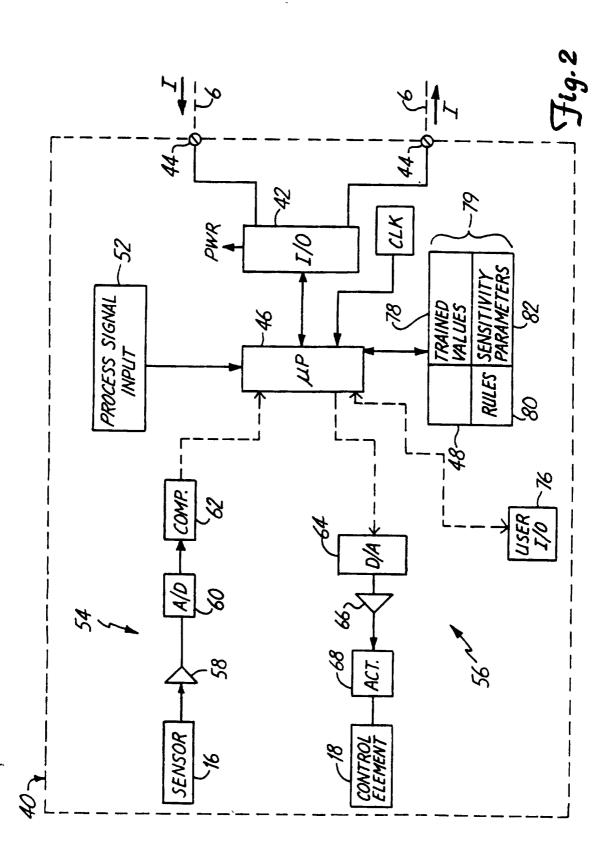
comparing statistical parameter to the nominal value in accordance with a relationship defined by the rule; and

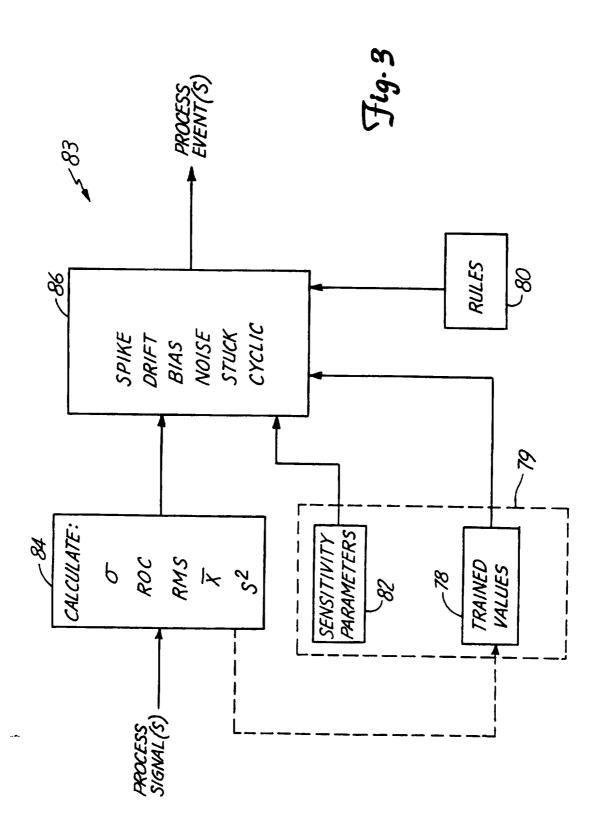
responsively providing a process event output based upon the step of comparing.

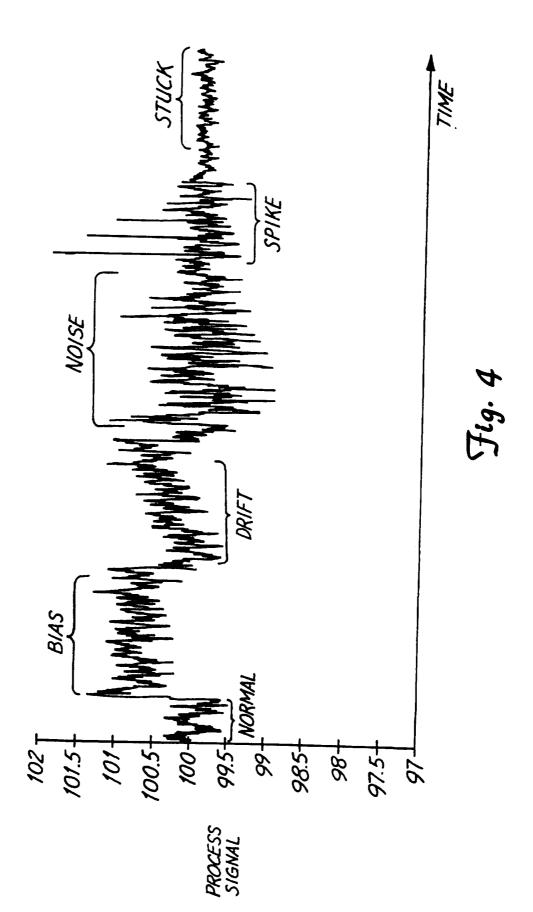
- 31. The method of claim 30 wherein the nominal parameter value comprises a trained value and a sensitivity parameter.
- 32. The method of claim 30 wherein the process signal comprises a process variable.
- 33. The method of claim 30 wherein the process signal comprises a control signal.
- 34. The method of claim 30 wherein the process signal comprises a diagnostic signal.
- 35. The method of claim 31 including calculating a statistical parameter of the process variable during normal operation and storing the statistical parameter in memory as the trained value.

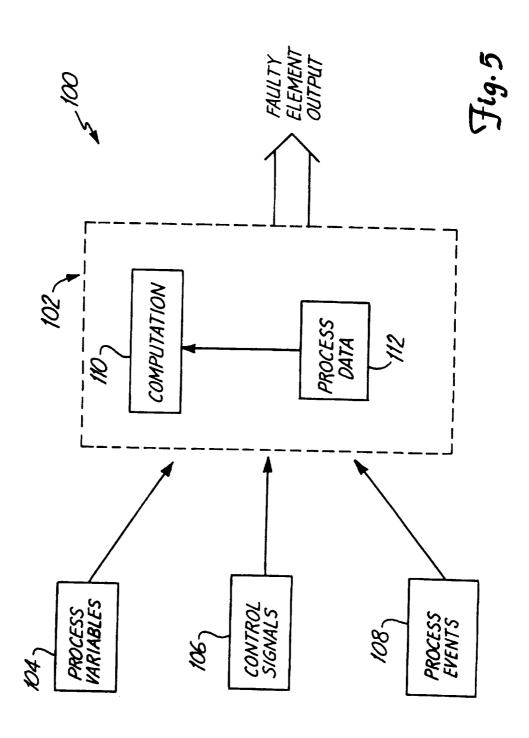
- 36. The method of claim 30 wherein the rules are selected from the group consisting of spike, drift, bias, noise and stuck.
- 37. The method of claim 30 wherein the statistical parameter is selected from the group consisting of standard deviation, mean, sample variance, root-mean-square (RMS), range, and rate of change.
- 38. The method of claim 30 wherein the step of comparing includes performing a fuzzy logic operation.











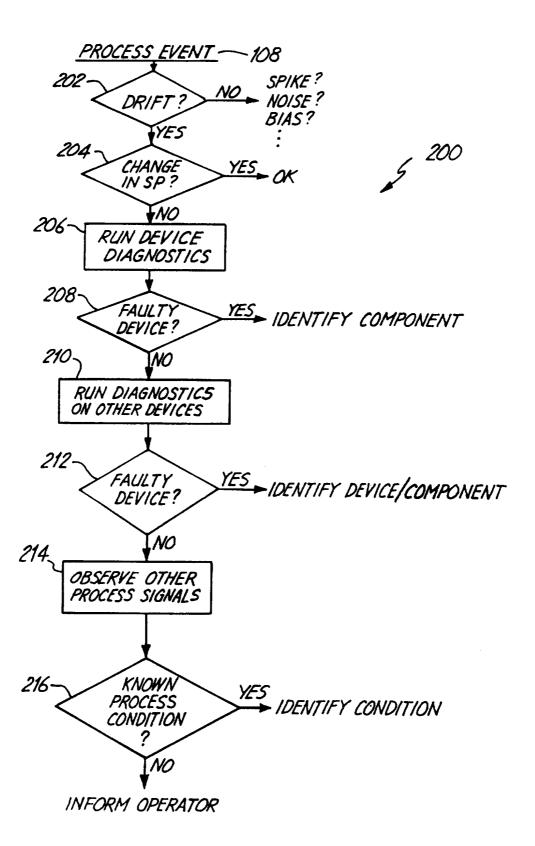


Fig. 6

## INTERNATIONAL SEARCH REPORT

Intern al Application No PCT/US 97/03859

A. CLAS	SIFICATION OF SUBJECT MATTER				
IPC 6	G05B13/02				
	•				
According	g to International Patent Classification (IPC) or to both national	- Inspification and IDC			
1	OS SEARCHED	classification and IPC			
	documentation searched (classification system followed by cla-	ssification symbols)			
IPC 6	G05B	- ,,			
Document	ation searched other than minimum documentation to the exten	t that such documents are included in the field	ds searched		
Electronic	data base consulted during the international search (name of da	ita base and, where practical, search terms use	:d)		
}			· <del>-</del> ,		
C. DOCUI	MENTS CONSIDERED TO BE RELEVANT				
Category *	Citation of document, with indication, where appropriate, of	the relevant nassages	B alamata at a M		
	,		Relevant to claim No.		
х	COMMUN.STATISTSIMULA,		1 5 20		
	vol. 24, no. 2, 1995, USA,		1,5,30, 32,37		
	pages 409-437, XP000675273		32,37		
	C.LOWRY ET AL: "THE PERFORMAN	CE OF			
	CONTROL CHARTS FOR MONITORING	PROCESS			
Y	VARIATION" see page 409, line 1 - page 41	4 line 12			
•	see page 405, Thie 1 - page 41	4, The 13	8,38		
Υ	DE 44 33 593 A (BUEHLER AG) 1	June 1995	8,38		
	see the whole document		0,50		
Χ	ED 0 644 470 A (NIDDON 51 50 TD				
^	EP 0 644 470 A (NIPPON ELECTRI March 1995	C CO) 22	23		
γ	see the whole document		27		
			27		
Y	EP 0 594 227 A (IBERDITAN S L)	27 April	27		
	1994				
	see the whole document				
1		-/			
		_/			
X Furth	ner documents are listed in the continuation of box C.	Patent family members are listed	in annex.		
Special cate	egories of cited documents:				
'A' docume	ent defining the general state of the art which is not	"T" later document published after the int or priority date and not in conflict w	th the annication but		
conside	ered to be of particular relevance locument but published on or after the international	cited to understand the principle or t invention	heory underlying the		
ining a	ate	"X" document of particular relevance; the cannot be considered novel or canno	claimed invention		
WILLCU IS	nt which may throw doubts on priority claim(s) or sited to establish the publication date of another	involve an inventive step when the de	ocument is taken alone		
citation	or other special reason (as specified) nt referring to an oral disclosure, use, exhibition or	"Y" document of particular relevance; the cannot be considered to involve an ir	entive sten when the		
outer m	leans	document is combined with one or ments, such combination being obvious	nore other such docu-		
later tha	nt published prior to the international filing date but an the priority date claimed	in the art.  "&" document member of the same patent	1		
Date of the a	ctual completion of the international search	Date of mailing of the international se			
26 	June 1997		1 5.07.97		
ame and ma	ailing address of the ISA	Authorized officer			
	European Patent Office, P.B. 5818 Patentiaan 2 NL - 2280 HV Rijswijk	1			
	Tel. (+31-70) 340-2040, Tx. 31 651 epo nl, Fax: (+31-70) 340-3016	Kelperis, K	İ		
	( - ** '0) 570-5010	I Weibering IV			

1

## INTERNATIONAL SEARCH REPORT

Intern: 1 Application No PCT/US 97/03859

		PCT/US 9//03859		
C.(Continu	DOCUMENTS CONSIDERED TO BE RELEVANT	19 days to a tare No		
Category °	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.		
X	US 5 053 815 A (WENDELL MICHAEL J) 1 October 1991 see the whole document	1,30		
X	US 5 440 478 A (FISHER GARY ET AL) 8 August 1995 see the whole document	1,30		
A	EP 0 487 419 A (SEIKO EPSON CORP) 27 May 1992 see the whole document	1,23,30		
A	PROCEEDINGS OF THE 13TH IFAC/IFIP WORKSHOP, 7 October 1985, USA, pages 29-38, XP000674189 R.WEISMAN: "ON-LINE STATISTICAL PROCESS CONTROL FOR A GLASS TANK INGREDIENT SCALE" see the whole document	1,23,30		
A	PROCEEDINGS OF THE IEEE INTERNATIONAL SYMPOSIUM ON INTELLIGENT CONTROL, 24 August 1988, USA, pages 736-741, XP000675296 P.LOVE ET AL: "A KNOWLEDGE BASED APPROACH FOR DETECTION AND DIAGNOSING OF OUT OF CONTROL EVENTS IN MANUFACTURING PROCESSES" see the whole document	1,7,23, 26,30,36		

## INTERNATIONAL SEARCH REPORT

Information on patent family members

Interna 1 Application No PCT/US 97/03859

Patent document cited in search report	Publication date _	Patent family member(s)	Publication date
DE 4433593 A	01-06-95	CH 687047 A	30-08-96
EP 0644470 A	22-03-95	JP 2546159 B JP 7040206 A US 5493501 A	23-10-96 10-02-95 20-02-96
EP 0594227 A	27-04-94	ES 2046114 A	16-01-94
US 5053815 A	01-10-91	NONE	•
US 5440478 A	08-08-95	NONE	
EP 0487419 A	27-05-92	JP 5019807 A US 5282139 A	29-01-93 25-01-94

Form PCT/ISA/210 (patent family annex) (July 1992)